


<b>Search Notes</b> 	<b>Application/Control No.</b> 10759642	<b>Applicant(s)/Patent Under Reexamination</b> ERIC YEH ET AL.
	<b>Examiner</b> PIERRE-LOUIS DESIR	<b>Art Unit</b> 2617

SEARCHED			
Class	Subclass	Date	Examiner
455	466, 412.1	9/24/2011	pd

SEARCH NOTES		
Search Notes	Date	Examiner
EAST	9/24/2011	pd

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
455	466, 412.1	9/24/2011	pd

	/PIERRE-LOUIS DESIR/ Primary Examiner.Art Unit 2617
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